Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination	
į	10/685,453	CHUNG, DAVID B.	
	Examiner	Art Unit	
	HOAN C. NGUYEN	2871	

SEARCHED					
Class	Subclass	Date	Examiner		
349/	2	8/26/2005	CHN		
			<u> </u>		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
east sewrch in USPUB, USPAT, EPO and JPO	8/26/2005	CHN		